

Boundary Scan Test Modules

for PCIe Loopback Test

Keysight Boundary Scan PCIE loopback test modules

- Tests PCIe high-speed signals to CPU or other PCIe devices using IEEE 1149.1 and IEEE 1149.6 loopback tests
- Enables Signal testing using 1149.1 interconnect
- Performs power tests and GND pins for *opens* on PCIe connector

PCIe test cards are available in assorted sizes; usable in both manual and auto-insert mode of operation:

- x8 – 96 pins
- x16 – 168 pins
- Additional sizes and custom pinouts for Riser card are available upon request



Benefits

- Easy to use
- Quick test development in minutes using library package
- Fast turn-on and easy debug with x1149 debug tools
- Covers power and all ground pins connectivity for high-speed signal return; critical for high-speed signal integrity

Top and bottom view of PCIe x16 connector loopback test card.



Top view





Bottom view

Features of PCIe x16

- Quickly tests PCIe differential interface signals on PCIe plug-in cards by looping back Tx to Rx
- Easy connectivity since they are gold finger bare board; no need to test power and GND pin
- Requires IEEE 1149.6 boundary-scan cell on the PCIe interface chip to test PCIe differential signals using IEEE 1149.6 interconnect test for AC coupled nodes
- Use with Keysight i3070

Available PCIe Loopback test cards

Model	Description	
TSCTK1801	BScan PCIe x8 loopback test card	
TSCTK1603	BScan PCIe x16 loopback test card	

Learn more at: www.keysight.com

For more information on Keysight Technologies' products, applications or services, please contact your local Keysight office. The complete list is available at: www.keysight.com/find/contactus



Find us at www.keysight.com

This information is subject to change without notice. © Keysight Technologies, 2018, Published in USA, September 10, 2018, 5992-3300EN